











TPA3251D2

ZHCSDT9C -JUNE 2015-REVISED JUNE 2015

TPA3251D2 175W 立体声/350W 单声道 PurePath™ 超高清模拟输入 D 类放大器

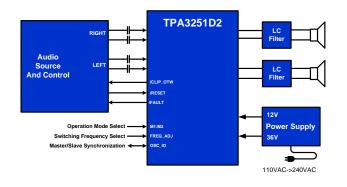
特性

- 差分模拟输入
- 总谐波失真+噪声 (THD+N) 为 10% 时的总输出功
 - 175W/4Ω, 桥接负载 (BTL) 立体声配置
 - 220W/3Ω, 桥接负载 (BTL) 立体声配置
 - 350W/2Ω, 并行桥接负载 (PBTL) 单声道配置
- THD+N 为 1% 时的总输出功率
 - 140W/4Ω, BTL 立体声配置
 - 175W/3Ω, BTL 立体声配置
 - 285W/2Ω, PBTL 单声道配置
- 采用高级集成反馈设计,具有高速栅极驱动器错误 校正功能

(PurePath™ 超高清)

- 高达 100kHz 的单宽带,用于高清 (HD) 源的高 频成分
- 超低 THD+N: 1W/4Ω 时为 0.005%; 削波时 <0.01%
- 60dB 电源抑制比 (PSRR)(BTL, 无输入信
- <60uV(A 加权)输出噪声
- >111dB(A加权)信噪比(SNR)
- 多种可能配置:
 - 立体声、单声道、2.1 和 4xSE
- 启动和停止时无喀哒声和噼啪声
- 90% 高效 D 类操作 (4Ω)
- 12V 至 36V 宽电源电压工作范围
- 具有错误报告功能的自保护设计(包括欠压、过 压、削波和短路保护)

简化电路原理图



采用推荐的系统设计时,符合电磁干扰 (EMI) 标准

2 应用

- 蓝光碟磁盘™ /DVD 接收器
- 高端 HTiB 系统
- AV 接收机
- 高端条形音箱
- 微型 Combo 系统
- 有源扬声器和低音炮

说明

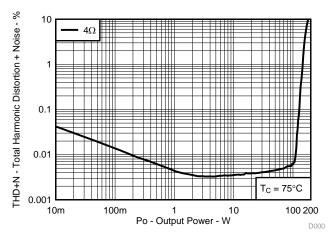
TPA3251D2 是一款高性能 D 类功率放大器,它具有 D 类效率并且能够带来真正的高端音质。 该器件特有 高级集成反馈设计和专有高速栅极驱动器错误校正功能 (PurePath™ 超高清)。 该技术可使器件在整个音频 频带内保持超低失真,同时展现完美音质。 该器件最 多可驱动 2 个 175W/4Ω 负载和 2 个 220W/3Ω 负载, 并且特有一个 2 VRMS 模拟输入接口,支持与高性能 DAC(例如, TI的 PCM5242)的无缝连接。除了出 色的音频性能外, TPA3251D2 还兼具高功率效率和超 低功率级空闲损耗(1W以下)两大优点。这可以利用 60mΩ MOSFET 以及优化型栅极驱动器方案来实现, 该方案相比传统的分立实现方案可显著降低空闲损耗。

器件信息(1)

	BB 11 1B 10:	
器件型号	封装	封装尺寸 (标称值)
TPA3251D2	HTSSOP (44)	6.10mm x 14.00mm

(1) 如需了解所有可用封装,请见数据表末尾的可订购产品附录。

总谐波失真





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	修订历史记录 ages from Revision B (June 2015) to Revision C				Page
• 🖯	是从单页"产品预览"更改为完整数据表				
Chan	ges from Revision A (June 2015) to Revision B				Page
	· 收炼性列表项"80dB 由源抑制化 (PSRR) (RTL、于输入信	是)"面已	<i>ከ</i> 'ዜ" ና	SOMR 由循抑制比 (PSRR)(RTI 子輪	λ信

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•	已更改特性列表中的 <i>THD+N 为 1% 时的总输出功率</i>	
•	已更改特性列表项"高级集成反馈设计"	
•	已将 特性 列表项"<65µV(A 加权)输出噪声"更改为"<60µV(A 加权)输出噪声"	
•	已更改 特性 列表中的"多种可能配置:"	
•	已更改 <i>说明</i>	



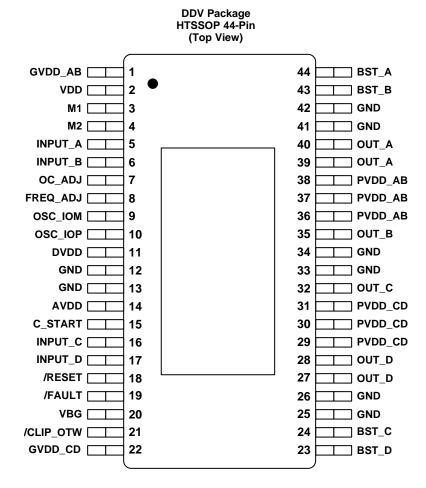
5 Device Comparison Table

DEVICE NAME	DESCRIPTION
TAS5630B	300-W Stereo Class-D PurePath™ HD Analog Input Audio Power Amplifier
TAS5613A	150-W Stereo Class-D PurePath™ HD Analog Input Audio Power Amplifier
TAS5611A	125-W Stereo Class-D PurePath™ HD Analog Input Audio Power Amplifier

6 Pin Configuration and Functions

The TPA3251D2 is available in a thermally enhanced TSSOP package.

The package type contains a heat slug that is located on the top side of the device for convenient thermal coupling to the heat sink.





Pin Functions

NAME	NO.	I/O	DESCRIPTION
AVDD	14	Р	Internal voltage regulator, analog section
BST_A	44	Р	HS bootstrap supply (BST), external 0.033 μF capacitor to OUT_A required.
BST_B	43	Р	HS bootstrap supply (BST), external 0.033 μF capacitor to OUT_B required.
BST_C	24	Р	HS bootstrap supply (BST), external 0.033 μF capacitor to OUT_C required.
BST_D	23	Р	HS bootstrap supply (BST), external 0.033 μF capacitor to OUT_D required.
CLIP_OTW	21	0	Clipping warning and Over-temperature warning; open drain; active low
C_START	15	0	Startup ramp, requires a charging capacitor to GND
DVDD	11	Р	Internal voltage regulator, digital section
FAULT	19	0	Shutdown signal, open drain; active low
FREQ_ADJ	8	0	Oscillator frequency programming pin
GND	12, 13, 25, 26, 33, 34, 41, 42	Р	Ground
GVDD_AB	1	Р	Gate-drive voltage supply; AB-side, requires 0.1 μF capacitor to GND
GVDD_CD	22	Р	Gate-drive voltage supply; CD-side, requires 0.1 μF capacitor to GND
INPUT_A	5	1	Input signal for half bridge A
INPUT_B	6	1	Input signal for half bridge B
INPUT_C	16	1	Input signal for half bridge C
INPUT_D	17	1	Input signal for half bridge D
M1	3	1	Mode selection 1 (LSB)
M2	4	1	Mode selection 2 (MSB)
OC_ADJ	7	I/O	Over-Current threshold programming pin
OSC_IOM	9	I/O	Oscillator synchronization interface
OSC_IOP	10	0	Oscillator synchronization interface
OUT_A	39, 40	0	Output, half bridge A
OUT_B	35	0	Output, half bridge B
OUT_C	32	0	Output, half bridge C
OUT_D	27, 28	0	Output, half bridge D
PVDD_AB	36, 37, 38	Р	PVDD supply for half-bridge A and B
PVDD_CD	29, 30, 31	Р	PVDD supply for half-bridge C and D
RESET	18	1	Device reset Input; active low
VDD	2	Р	Power supply for internal voltage regulator requires a 10-µF capacitor with a 0.1-µF capacitor to GND for decoupling.
VBG	20	Р	Internal voltage reference requires a 0.1-µF capacitor to GND for decoupling.
PowerPad™		Р	Ground, connect to grounded heat sink

Table 1. Mode Selection Pins

MODE PINS		INPUT MODE	OUTPUT	DESCRIPTION			
M2	M1	INPUT WICHE	CONFIGURATION	DESCRIPTION			
0	0 0 2N + 1 2 × BTL		2 × BTL	Stereo BTL output configuration			
0	1	2N/1N + 1	1 x BTL + 2 x SE	2.1 BTL + SE mode			
1	0	2N + 1	1 x PBTL	Parallelled BTL configuration. Connect INPUT_C and INPUT_D to GND.			
1	1	1N +1	4 x SE	Single ended output configuration			



7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted) (1)

		MIN	MAX	UNIT
	BST_X to GVDD_X ⁽²⁾	-0.3	50	V
	VDD to GND	-0.3	13.2	V
	GVDD_X to GND ⁽²⁾	-0.3	13.2	V
Supply voltage	PVDD_X to GND ⁽²⁾	-0.3	50	V
	DVDD to GND	-0.3	4.2	V
	AVDD to GND	-0.3	8.5	V
	VBG to GND	-0.3	4.2	V
	OUT_X to GND ⁽²⁾	-0.3	50	V
	BST_X to GND ⁽²⁾	-0.3	62.5	V
	OC_ADJ, M1, M2, OSC_IOP, OSC_IOM, FREQ_ADJ, C_START, to GND	-0.3	4.2	V
Interface pins	RESET, FAULT, CLIP_OTW, CLIP to GND	-0.3	4.2	V
	INPUT_X to GND	-0.3	7	V
	Continuous sink current, RESET, FAULT, CLIP_OTW, CLIP, RESET to GND		9	mA
TJ	Operating junction temperature range	0	150	°C
T _{stg}	Storage temperature range	-40	150	°C

⁽¹⁾ Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

7.2 ESD Ratings

			VALUE	UNIT
V _{ESD} Electrostatic discharge	Floatroctatio disabores	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±2000	V
	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	±500	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

⁽²⁾ These voltages represents the DC voltage + peak AC waveform measured at the terminal of the device in all conditions.

⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

			MIN	TYP	MAX	UNIT
PVDD_x	Half-bridge supply	DC supply voltage	12	36	38	V
GVDD_x	Supply for logic regulators and gate-drive circuitry	DC supply voltage	10.8	12	13.2	V
VDD	Digital regulator supply voltage	DC supply voltage	10.8	12	13.2	V
R _L (BTL)			2.7	4		
R _L (SE)	Load impedance	Output filter inductance within recommended value range	1.5	3		Ω
R _L (PBTL)		Toolimended value range	1.6	2		
L _{OUT} (BTL)			5			
L _{OUT} (SE)	Output filter inductance	Minimum output inductance at I _{OC}	5			μH
L _{OUT} (PBTL)			5			
	PWM frame rate selectable for AM interference avoidance; 1% Resistor tolerance	Nominal	575	600	625	kHz
F _{PWM}		AM1	475	500	525	
		AM2	430	450	470	
		Nominal; Master mode	9.9	10	10.1	kΩ
$R_{(FREQ_ADJ)}$	PWM frame rate programming resistor	AM1; Master mode	19.8	20	20.2	
,		AM2; Master mode	29.7	30	30.3	
C _{PVDD}	PVDD close decoupling capacitors			1.0		μF
R _{OC}	Over-current programming resistor	Resistor tolerance = 5%	22		30	kΩ
R _{OC(LATCHED)}	Over-current programming resistor	Resistor tolerance = 5%	47		64	kΩ
V _(FREQ_ADJ)	Voltage on FREQ_ADJ pin for slave mode operation	Slave mode		3.3		٧
T _J	Junction temperature		0		125	°C

7.4 Thermal Information

		TPA3	251D2	
THERMAL METRIC ⁽¹⁾		DDV 44-PIN		
	THERMAL METRIC(1)	JEDEC STANDARD 4 LAYER PCB	FIXED 85°C HEATSINK TEMPERATURE ⁽²⁾	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance	50.7	2.5 ⁽²⁾	
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	0.36	0.2	
$R_{\theta JB}$	Junction-to-board thermal resistance	24.4	n/a	°C/W
ΨЈТ	Junction-to-top characterization parameter	0.19	0.5	*C/VV
ΨЈВ	Junction-to-board characterization parameter	24.2	n/a	
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	n/a	n/a	

⁽¹⁾ For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

⁽²⁾ Thermal data are obtained with 85°C heat sink temperature using thermal compound with 0.7W/mK thermal conductivity and 2mil thickness. In this model heat sink temperature is considered to be the ambient temperature and only path for dissipation is to the heatsink.



7.5 Electrical Characteristics

PVDD_X = 36 V, GVDD_X = 12 V, VDD = 12 V, T_C (Case temperature) = 75°C, f_S = 600 kHz, unless otherwise specified.

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
INTERNAL VOLTAG	SE REGULATOR AND CURRENT CONSUMPT	TION				
DVDD	Voltage regulator, only used as reference node	VDD = 12 V	3	3.3	3.6	V
AVDD	Voltage regulator, only used as reference node	VDD = 12 V		7.8		V
	1/00	Operating, 50% duty cycle		40		
I _{VDD}	VDD supply current	Idle, reset mode		13		mA
	Coto complex compact and full being	50% duty cycle		25		A
I _{GVDD_X}	Gate-supply current per full-bridge	Reset mode		3		mA
	DVDD idle sussesses as full baider	50% duty cycle with recommended output filter		12.5		mA
I _{PVDD_X}	PVDD idle current per full bridge	Reset mode, No switching		1		mA
ANALOG INPUTS						
R _{IN}	Input resistance			24		kΩ
V _{IN}	Maximum input voltage swing				7	V
I _{IN}	Maximum input current				1	mA
G	Inverting voltage Gain	V _{OUT} /V _{IN}		20		dB
OSCILLATOR						
	Nominal, Master Mode	F _{PWM} × 6	3.45	3.6	3.75	
f _{OSC(IO+)}	AM1, Master Mode		2.85	3	3.15	MHz
	AM2, Master Mode		2.58	2.7	2.82	
V _{IH}	High level input voltage		1.86			V
V _{IL}	Low level input voltage				1.45	V
OUTPUT-STAGE M	OSFETs					
D	Drain-to-source resistance, low side (LS)	T _J = 25°C, Includes metallization resistance,		60	100	mΩ
R _{DS(on)}	Drain-to-source resistance, high side (HS)	GVDD = 12 V		60	100	mΩ
I/O PROTECTION			•			
$V_{uvp,VDD,GVDD}$	Undervoltage protection limit, GVDD_x and VDD			9.5		V
V _{uvp,VDD, GVDD,hyst} (1)				0.6		V
OTW	Overtemperature warning, CLIP_OTW(1)		115	125	135	°C
OTW _{hyst} ⁽¹⁾	Temperature drop needed below OTW temperature for CLIP_OTW to be inactive after OTW event.			25		°C
OTE ⁽¹⁾	Overtemperature error		145	155	165	°C
OTE-OTW _(differential)	OTE-OTW differential			30		°C
OTE _{hyst} ⁽¹⁾	A reset needs to occur for FAULT to be released following an OTE event			25		°C
OLPC	Overload protection counter	f _{PWM} = 600 kHz		1.7		ms
I _{oc}	Overcurrent limit protection	Resistor – programmable, nominal peak current in 1Ω load, R_{OCP} = 22 $k\Omega$		14		А
OC(LATCHED)	Overcurrent limit protection	Resistor – programmable, peak current in 1Ω load, $R_{OCP}=47k\Omega$		14		Α
I _{DCspkr}	DC Speaker Protection Current Threshold	BTL current imbalance threshold		1.5		Α
I _{OCT}	Overcurrent response time	Time from switching transition to flip-state induced by overcurrent.		150		ns
I _{PD}	Output pulldown current of each half	Connected when RESET is active to provide bootstrap charge. Not used in SE mode.		3		mA

⁽¹⁾ Specified by design.



Electrical Characteristics (continued)

 $PVDD_X = 36 \text{ V}$, $GVDD_X = 12 \text{ V}$, VDD = 12 V, T_C (Case temperature) = 75°C, $f_S = 600 \text{ kHz}$, unless otherwise specified.

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
STATIC DIGITAL	SPECIFICATIONS					
V _{IH}	High level input voltage	M4 M2 OSC IOD OSC IOM DESET	1.9			V
V _{IL}	Low level input voltage	M1, M2, OSC_IOP, OSC_IOM, RESET			0.8	V
I _{lkg}	Input leakage current				100	μΑ
OTW/SHUTDOW	N (FAULT)					
R _{INT_PU}	Internal pullup resistance, CLIP_OTW to DVDD, FAULT to DVDD		20	26	32	kΩ
V _{OH}	High level output voltage	Internal pullup resistor	3	3.3	3.6	V
V _{OL}	Low level output voltage	I _O = 4 mA		200	500	mV
Device fanout	CLIP_OTW, FAULT	No external pullup		30		devices

7.6 Audio Characteristics (BTL)

PCB and system configuration are in accordance with recommended guidelines. Audio frequency = 1 kHz, PVDD_X = 36 V, GVDD_X = 12 V, R_L = 4 Ω , f_S = 600 kHz, R_{OC} = 22 k Ω , T_C = 75°C, Output Filter: L_{DEM} = 10 μ H, C_{DEM} = 1 μ F, mode = 00, AES17 + AUX-0025 measurement filters,unless otherwise noted.

	PARAMETER	TEST CONDITIONS	MIN TYP	MAX	UNIT
		R _L = 3 Ω, 10% THD+N	220		
D	Dower output per channel	$R_L = 4 \Omega$, 10% THD+N	175		W
Po	Power output per channel	$R_L = 3 \Omega$, 1% THD+N	175		VV
		$R_L = 4 \Omega$, 1% THD+N	140		
THD+N	Total harmonic distortion + noise	1 W	0.005%		
V _n	Output integrated noise	A-weighted, AES17 filter, Input Capacitor Grounded	60		μV
Vos	Output offset voltage	Inputs AC coupled to GND	20	60	mV
SNR	Signal-to-noise ratio ⁽¹⁾		111		dB
DNR	Dynamic range		115		dB
P _{idle}	Power dissipation due to Idle losses (I _{PVDD_X})	P _O = 0, 4 channels switching ⁽²⁾	1		W

⁽¹⁾ SNR is calculated relative to 1% THD+N output level.

⁽²⁾ Actual system idle losses also are affected by core losses of output inductors.



7.7 Audio Characteristics (SE)

PCB and system configuration are in accordance with recommended guidelines. Audio frequency = 1 kHz, PVDD_X = 36 V, GVDD_X = 12 V, R_L = 2 Ω , f_S = 600 kHz, R_{OC} = 22 k Ω , T_C = 75°C, Output Filter: L_{DEM} = 15 μ H, C_{DEM} = 1 μ F, MODE = 11, AES17 + AUX-0025 measurement filters, unless otherwise noted.

	PARAMETER	TEST CONDITIONS	MIN TYP M	IAX UNIT			
		$R_L = 2 \Omega$, 10% THD+N	84				
		$R_L = 3 \Omega$, 10% THD+N	60				
D	Davis autout van akanaal	$R_L = 4 \Omega$, 10% THD+N	47	w			
Po	Power output per channel	$R_L = 2 \Omega$, 1% THD+N	67	VV			
		$R_L = 3 \Omega$, 1% THD+N					
		$R_L = 4 \Omega$, 1% THD+N	37				
THD+N	Total harmonic distortion + noise	1 W	0.015%				
V _n	Output integrated noise	A-weighted, AES17 filter, Input Capacitor Grounded	115	μV			
SNR	Signal to noise ratio ⁽¹⁾	A-weighted	100	dB			
DNR	Dynamic range	A-weighted	101	dB			
P _{idle}	Power dissipation due to idle losses (IPVDD_X)	P _O = 0, 4 channels switching ⁽²⁾	0.5	W			

⁽¹⁾ SNR is calculated relative to 1% THD+N output level.

7.8 Audio Characteristics (PBTL)

PCB and system configuration are in accordance with recommended guidelines. Audio frequency = 1 kHz, PVDD_X = 36 V, GVDD_X = 12 V, $R_L = 2~\Omega$, $f_S = 600$ kHz, $R_{OC} = 22~k\Omega$, $T_C = 75^{\circ}C$, Output Filter: $L_{DEM} = 10~\mu\text{H}$, $C_{DEM} = 1~\mu\text{F}$, MODE = 10, AES17 + AUX-0025 measurement filters, unless otherwise noted.

	PARAMETER	TEST CONDITIONS	MIN TYP MAX	UNIT
		R _L = 2 Ω, 10% THD+N	355	
		$R_L = 3 \Omega$, 10% THD+N	250	
Б		$R_L = 4 \Omega$, 10% THD+N	195	10/
Po	Power output per channel	$R_L = 2 \Omega$, 1% THD+N	285	W
		$R_L = 3 \Omega$, 1% THD+N	200	
		$R_L = 4 \Omega$, 1% THD+N	155	
THD+N	Total harmonic distortion + noise	1 W	0.05%	
V _n	Output integrated noise	A-weighted, AES17 filter, Input Capacitor Grounded	62	μV
SNR	Signal to noise ratio ⁽¹⁾	A-weighted	111	dB
DNR	Dynamic range	A-weighted	111	dB
P _{idle}	Power dissipation due to idle losses (IPVDD_X)	P _O = 0, 4 channels switching ⁽²⁾	1	W

⁽¹⁾ SNR is calculated relative to 1% THD+N output level.

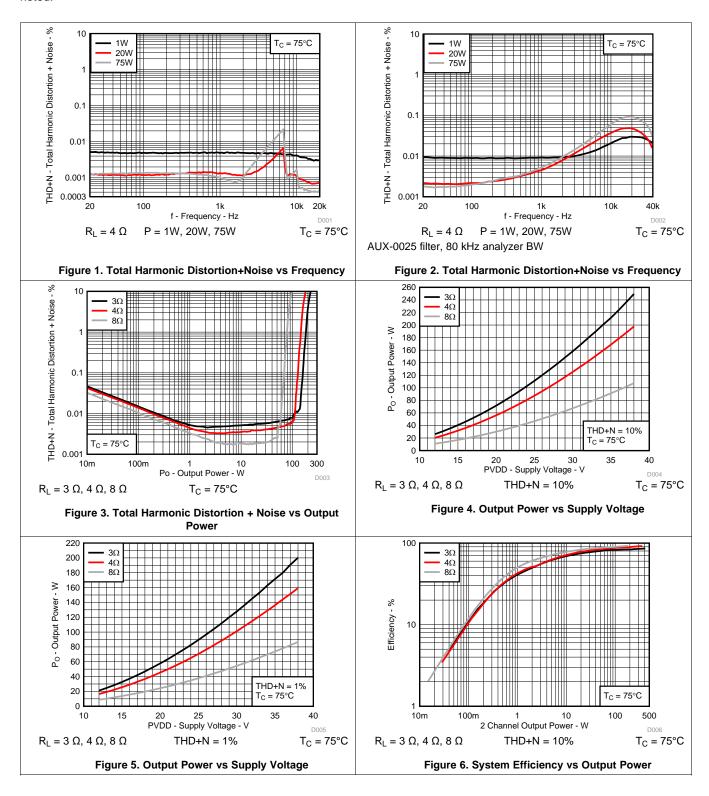
⁽²⁾ Actual system idle losses are affected by core losses of output inductors.

⁽²⁾ Actual system idle losses are affected by core losses of output inductors.



7.9 Typical Characteristics, BTL Configuration

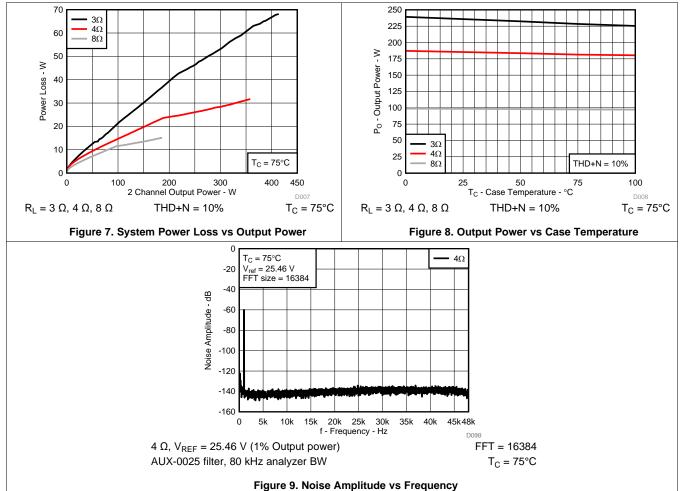
All Measurements taken at audio frequency = 1 kHz, PVDD_X = 36 V, GVDD_X = 12 V, R_L = 4 Ω , f_S = 600 kHz, R_{OC} = 22 k Ω , T_C = 75°C, Output Filter: L_{DEM} = 10 μ H, C_{DEM} = 1 μ F, mode = 00, AES17 + AUX-0025 measurement filters,unless otherwise noted.





Typical Characteristics, BTL Configuration (continued)

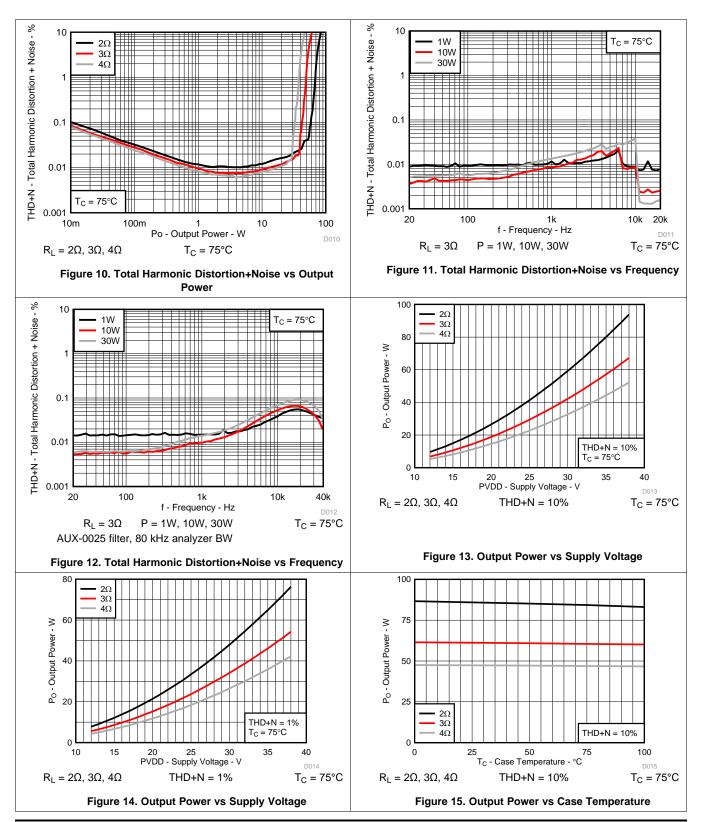
All Measurements taken at audio frequency = 1 kHz, PVDD_X = 36 V, GVDD_X = 12 V, R_L = 4 Ω , f_S = 600 kHz, R_{OC} = 22 k Ω , T_C = 75°C, Output Filter: L_{DEM} = 10 μ H, C_{DEM} = 1 μ F, mode = 00, AES17 + AUX-0025 measurement filters,unless otherwise noted.





7.10 Typical Characteristics, SE Configuration

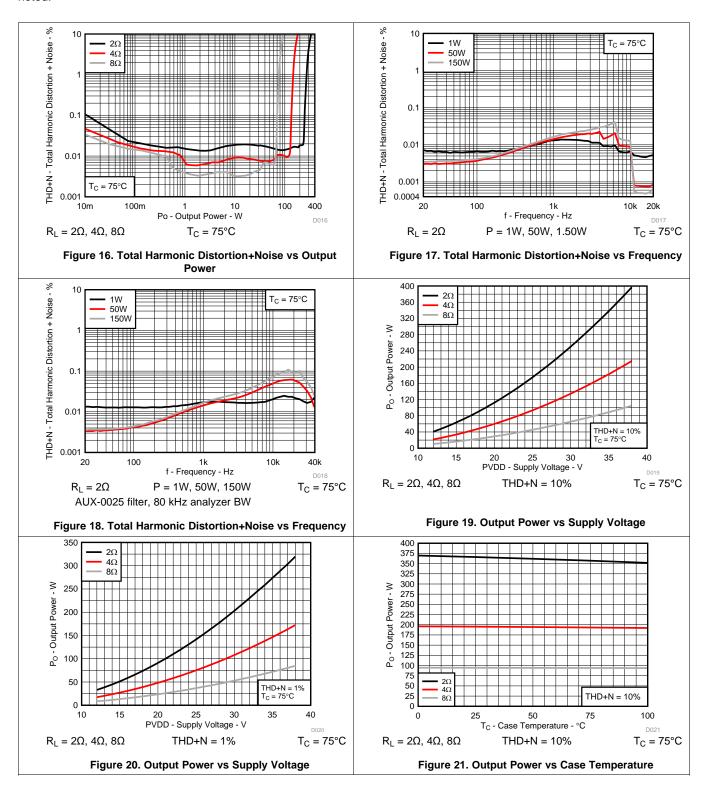
All Measurements taken at audio frequency = 1 kHz, PVDD_X = 36 V, GVDD_X = 12 V, R_L = 3 Ω , f_S = 600 kHz, R_{OC} = 22 k Ω , T_C = 75°C, Output Filter: L_{DEM} = 15 μ H, C_{DEM} = 680 nF, MODE = 11, AES17 + AUX-0025 measurement filters, unless otherwise noted.





7.11 Typical Characteristics, PBTL Configuration

All Measurements taken at audio frequency = 1kHz, PVDD_X = 36V, GVDD_X = 12V, $R_L = 2\Omega$, $f_S = 600$ kHz, $R_{OC} = 22k\Omega$, $T_C = 75^{\circ}$ C, Output Filter: $L_{DEM} = 10\mu$ H, $C_{DEM} = 1$ μ F, MODE = 10, AES17 + AUX-0025 measurement filters, unless otherwise noted.





8 Parameter Measurement Information

All parameters are measured according to the conditions described in the Recommended Operating Conditions, Typical Characteristics, BTL Configuration, Typical Characteristics, SE Configuration and Typical Characteristics, PBTL Configuration sections.

Most audio analyzers will not give correct readings of Class-D amplifiers' performance due to their sensitivity to out of band noise present at the amplifier output. AES-17 + AUX-0025 pre-analyzer filters are recommended to use for Class-D amplifier measurements. In absence of such filters, a 30-kHz low-pass filter (10 Ω + 47 nF) can be used to reduce the out of band noise remaining on the amplifier outputs.

9 Detailed Description

9.1 Overview

To facilitate system design, the TPA3251D2 needs only a 12-V supply in addition to the (typical) 36-V power-stage supply. An internal voltage regulator provides suitable voltage levels for the digital and low-voltage analog circuitry, AVDD and DVDD. Additionally, all circuitry requiring a floating voltage supply, that is, the high-side gate drive, is accommodated by built-in bootstrap circuitry requiring only an external capacitor for each half-bridge.

The audio signal path including gate drive and output stage is designed as identical, independent half-bridges. For this reason, each half-bridge has separate bootstrap pins (BST_X). Power-stage supply pins (PVDD_X) and gate drive supply pins (GVDD_X) are separate for each full bridge. Although supplied from the same 12-V source, separating to GVDD_AB, GVDD_CD, and VDD on the printed-circuit board (PCB) by RC filters (see application diagram for details) is recommended. These RC filters provide the recommended high-frequency isolation. Special attention should be paid to placing all decoupling capacitors as close to their associated pins as possible. In general, the physical loop with the power supply pins, decoupling capacitors and GND return path to the device pins must be kept as short as possible and with as little area as possible to minimize induction (see reference board documentation for additional information).

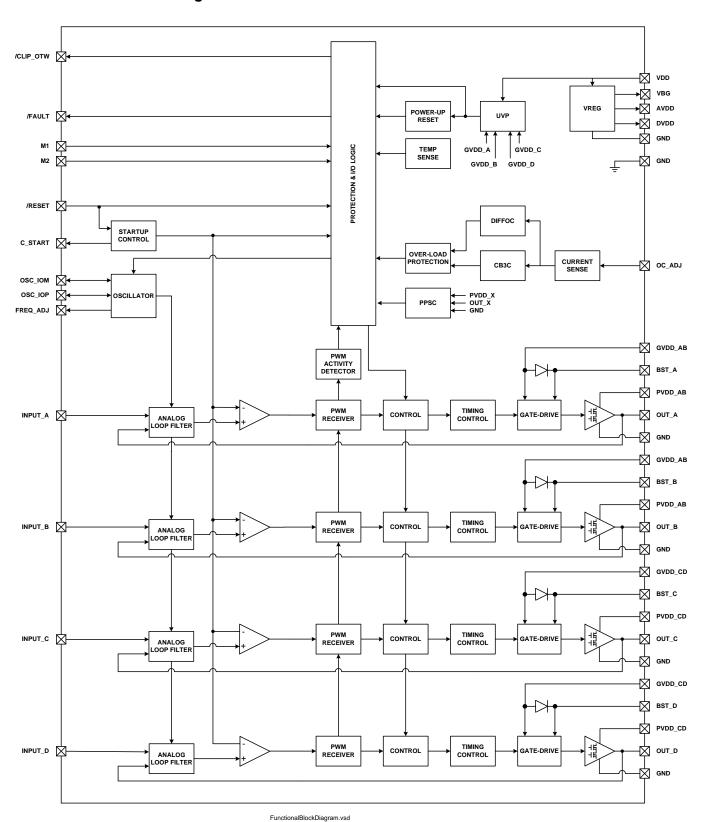
For a properly functioning bootstrap circuit, a small ceramic capacitor must be connected from each bootstrap pin (BST_X) to the power-stage output pin (OUT_X). When the power-stage output is low, the bootstrap capacitor is charged through an internal diode connected between the gate-drive power-supply pin (GVDD_X) and the bootstrap pins. When the power-stage output is high, the bootstrap capacitor potential is shifted above the output potential and thus provides a suitable voltage supply for the high-side gate driver. It is recommended to use 33-nF ceramic capacitors, size 0603 or 0805, for the bootstrap supply. These 33nF capacitors ensure sufficient energy storage, even during minimal PWM duty cycles, to keep the high-side power stage FET (LDMOS) fully turned on during the remaining part of the PWM cycle.

Special attention should be paid to the power-stage power supply; this includes component selection, PCB placement, and routing. As indicated, each full-bridge has independent power-stage supply pins (PVDD_X). For optimal electrical performance, EMI compliance, and system reliability, it is important that each PVDD_X node is decoupled with 1-µF ceramic capacitor placed as close as possible to the supply pins. It is recommended to follow the PCB layout of the TPA3251D2 reference design. For additional information on recommended power supply and required components, see the application diagrams in this data sheet.

The 12-V supply should be from a low-noise, low-output-impedance voltage regulator. Likewise, the 36-V power-stage supply is assumed to have low output impedance and low noise. The power-supply sequence is not critical as facilitated by the internal power-on-reset circuit, but it is recommended to release RESET after the power supply is settled for minimum turn on audible artefacts. Moreover, the TPA3251D2 is fully protected against erroneous power-stage turn on due to parasitic gate charging. Thus, voltage-supply ramp rates (dV/dt) are non-critical within the specified range (see the *Recommended Operating Conditions* table of this data sheet).



9.2 Functional Block Diagrams



TEXAS INSTRUMENTS

Functional Block Diagrams (continued)

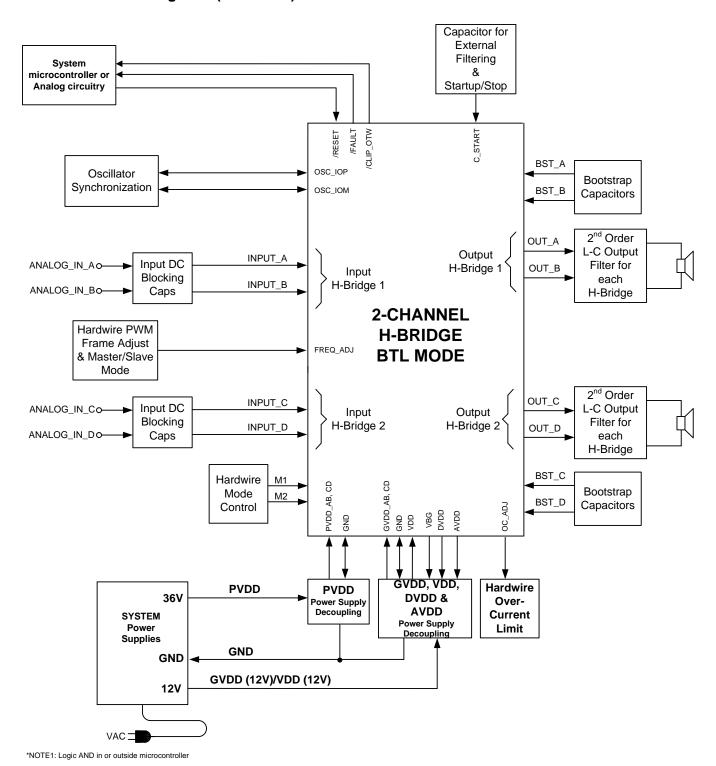


Figure 22. System Block Diagram



9.3 Feature Description

9.3.1 Error Reporting

The FAULT, and CLIP_OTW, pins are active-low, open-drain outputs. The function is for protection-mode signaling to a system-control device.

Any fault resulting in device shutdown is signaled by the FAULT pin going low. Also, CLIP_OTW goes low when the device junction temperature exceeds 125°C (see Table 2).

FAULT CLIP OTW **DESCRIPTION** Overtemperature (OTE) or overload (OLP) or undervoltage (UVP) Junction 0 0 temperature higher than 125°C (overtemperature warning) Overload (OLP) or undervoltage (UVP). Junction temperature higher than 125°C 0 0 (overtemperature warning) Overload (OLP) or undervoltage (UVP). Junction temperature lower than 125°C 0 1 0 Junction temperature higher than 125°C (overtemperature warning) 1 1 1 Junction temperature lower than 125°C and no OLP or UVP faults (normal operation)

Table 2. Error Reporting

Note that asserting either RESET low forces the FAULT signal high, independent of faults being present. TI recommends monitoring the CLIP_OTW signal using the system microcontroller and responding to an overtemperature warning signal by, that is, turning down the volume to prevent further heating of the device resulting in device shutdown (OTE).

To reduce external component count, an internal pullup resistor to 3.3 V is provided on both FAULT and CLIP_OTW outputs.

9.4 Device Protection System

The TPA3251D2 contains advanced protection circuitry carefully designed to facilitate system integration and ease of use, as well as to safeguard the device from permanent failure due to a wide range of fault conditions such as short circuits, overload, overtemperature, and undervoltage. The TPA3251D2 responds to a fault by immediately setting the power stage in a high-impedance (Hi-Z) state and asserting the FAULT pin low. In situations other than overload and overtemperature error (OTE), the device automatically recovers when the fault condition has been removed, that is, the supply voltage has increased.

The device will function on errors, as shown in Table 3.

BTL MODE **PBTL** MODE SE MODE LOCAL LOCAL LOCAL **TURNS OFF TURNS OFF TURNS OFF ERROR IN ERROR IN ERROR IN** Α Α Α A+B A+B В В В A+B+C+D С С С C+D C+D D D D

Table 3. Device Protection

Bootstrap UVP does not shutdown according to the table, it shuts down the respective halfbridge (non-latching, does not assert FAULT).

9.4.1 Overload and Short Circuit Current Protection

TPA3251D2 has fast reacting current sensors with a programmable trip threshold (OC threshold) on all high-side and low-side FETs. To prevent output current to increase beyond the programmed threshold, TPA3251D2 has the option of either limiting the output current for each switching cycle (Cycle By Cycle Current Control, CB3C) or to perform an immediate shutdown of the output in case of excess output current (Latching Shutdown). CB3C prevents premature shutdown due to high output current transients caused by high level music transients and a drop of real speaker's load impedance, and allows the output current to be limited to a maximum programmed



level. If the maximum output current persists, i.e. the power stage being overloaded with too low load impedance, the device will shut down the affected output channel and the affected output is put in a high-impedance (Hi- Z) state until a RESET cycle is initiated. CB3C works individually for each half bridge output. If an over current event is triggered, CB3C performs a state flip of the half bridge output that is cleared upon beginning of next PWM frame.

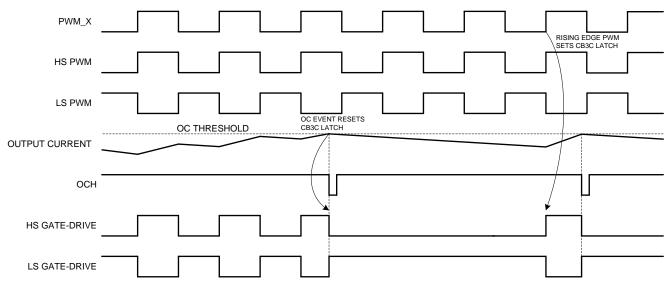


Figure 23. CB3C Timing Example

During CB3C an over load counter increments for each over current event and decrease for each non-over current PWM cycle. This allows full amplitude transients into a low speaker impedance without a shutdown protection action. In the event of a short circuit condition, the over current protection limits the output current by the CB3C operation and eventually shut down the affected output if the overload counter reaches its maximum value. If a latched OC operation is required such that the device shuts down the affected output immediately upon first detected over current event, this protection mode should be selected. The over current threshold and mode (CB3C or Latched OC) is programmed by the OC_ADJ resistor value. The OC_ADJ resistor needs to be within its intentional value range for either CB3C operation or Latched OC operation.

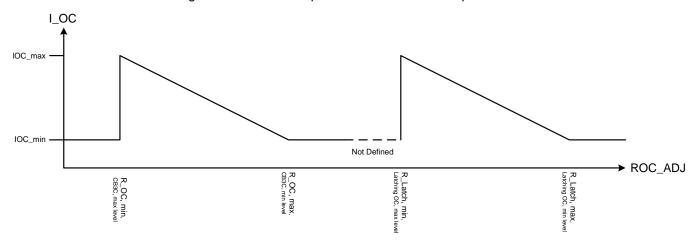


Figure 24. OC Threshold versus OC ADJ Resistor Value Example

OC_ADJ values outside specified value range for either CB3C or latched OC operation will result in minimum OC threshold.



Table 4. Device Protection

OC_ADJ Resistor Value	Protection Mode	OC Threshold
22kΩ	CB3C	16.3A
24kΩ	CB3C	15.1A
27kΩ	CB3C	13.5A
30kΩ	CB3C	12.3A
47kΩ	Latched OC	16.3A
51kΩ	Latched OC	15.1A
56kΩ	Latched OC	13.5A
64kΩ	Latched OC	12.3A

9.4.2 DC Speaker Protection

The output DC protection scheme protects a connected speaker from excess DC current caused by a speaker wire accidentally shorted to chassis ground. Such a short circuit results in a DC voltage of PVDD/2 across the speaker, which potentially can result in destructive current levels. The output DC protection detects any unbalance of the output and input current of a BTL output, and in the event of the unbalance exceeding a programmed threshold, the overload counter increments until its maximum value and the affected output channel is shut down. DC Speaker Protection is disabled in PBTL and SE mode operation.

9.4.3 Pin-to-Pin Short Circuit Protection (PPSC)

The PPSC detection system protects the device from permanent damage in the case that a power output pin (OUT_X) is shorted to GND_X or PVDD_X. For comparison, the OC protection system detects an overcurrent after the demodulation filter where PPSC detects shorts directly at the pin before the filter. PPSC detection is performed at startup i.e. when VDD is supplied, consequently a short to either GND_X or PVDD_X after system startup does not activate the PPSC detection system. When PPSC detection is activated by a short on the output, all half bridges are kept in a Hi-Z state until the short is removed; the device then continues the startup sequence and starts switching. The detection is controlled globally by a two step sequence. The first step ensures that there are no shorts from OUT_X to GND_X, the second step tests that there are no shorts from OUT_X to PVDD_X. The total duration of this process is roughly proportional to the capacitance of the output LC filter. The typical duration is < 15ms/µF. While the PPSC detection is in progress, FAULT is kept low, and the device will not react to changes applied to the RESET pin. If no shorts are present the PPSC detection passes, and FAULT is released. A device reset will not start a new PPSC detection. PPSC detection is enabled in BTL and PBTL output configurations, the detection is not performed in SE mode. To make sure not to trip the PPSC detection system it is recommended not to insert a resistive load to GND_X or PVDD_X.

9.4.4 Overtemperature Protection OTW and OTE

TPA3251D2 has a two-level temperature-protection system that asserts an active-low warning signal (CLIP_OTW) when the device junction temperature exceeds 125°C (typical) and, if the device junction temperature exceeds 155°C (typical), the device is <u>put into</u> thermal shutdown, resulting in all half-bridge outputs being set in the high-impedance (Hi-Z) state and FAULT being asserted low. OTE is latched in this case. To clear the OTE latch, RESET must be asserted. Thereafter, the device resumes normal operation.

9.4.5 Undervoltage Protection (UVP) and Power-on Reset (POR)

The UVP and POR circuits of the TPA3251D2 fully protect the device in any power-up/down and brownout situation. While powering up, the POR circuit resets the overload circuit (OLP) and ensures that all circuits are fully operational when the GVDD_X and VDD supply voltages reach stated in the *Electrical Characteristics* table. Although GVDD_X and VDD are independently monitored, a supply voltage drop below the UVP threshold on any VDD or GVDD_X pin results in all half-bridge outputs immediately being set in the high-impedance (Hi-Z) state and FAULT being asserted low. The device automatically resumes operation when all supply voltages have increased above the UVP threshold.

9.4.6 Fault Handling

If a fault situation occurs while in operation, the device acts accordingly to the fault being a global or a channel fault. A global fault is a chip-wide fault situation and causes all PWM activity of the device to be shut down, and will assert FAULT low. A global fault is a latching fault and clearing FAULT and restart operation requires resetting the device by toggling RESET. Toggling RESET should never be allowed with excessive system temperature, so it is advised to monitor RESET by a system microcontroller and only allow releasing RESET (RESET high) if the OTW signal is cleared (high). A channel fault results in shutdown of the PWM activity of the affected channel(s). Note that asserting RESET low forces the FAULT signal high, independent of faults being present. TI recommends monitoring the OTW signal using the system micro controller and responding to an over temperature warning signal by, that is, turning down the volume to prevent further heating of the device resulting in device shutdown (OTE).

Table 5. Error Reporting

Fault/Event	Fault/Event Description	Global or Channel	Reporting Method	Latched/Self Clearing	Action needed to Clear	Output FETs
PVDD_X UVP						
VDD UVP	Voltage Fault	Global	FAULT pin	Self Clearing	Increase affected supply voltage	HI-Z
AVDD UVP					oupply vollage	
POR (DVDD UVP)	Power On Reset	Global	FAULT pin	Self Clearing	Allow DVDD to rise	HI-Z
BST_X UVP	Voltage Fault	Channel (Half Bridge)	None	Self Clearing	Allow BST cap to recharge (lowside ON, VDD 12V)	HighSide off
OTW	Thermal Warning	Global	OTW pin	Self Clearing	Cool below OTW threshold	Normal operation
OTE	Thermal Shutdown	Global	FAULT pin	Latched	Toggle RESET	HI-Z
OLP (CB3C>1.7ms)	OC Shutdown	Channel	FAULT pin	Latched	Toggle RESET	HI-Z
Latched OC (47kΩ <roc_adj<68 kΩ)</roc_adj<68 	OC Shutdown	Channel	FAULT pin	Latched	Toggle RESET	HI-Z
CB3C (22kΩ <roc_adj<30 kΩ)</roc_adj<30 	OC Limiting	Channel	None	Self Clearing	Reduce signal level or remove short	Flip state, cycle by cycle at fs/3
Stuck at Fault ⁽¹⁾	No OSC_IO activity in Slave Mode	Global	None	Self Clearing	Resume OSC_IO activity	HI-Z

⁽¹⁾ Stuck at Fault occurs when input OSC_IO input signal frequency drops below minimum frequency given in the *Electrical Characteristics* table of this data sheet.

9.4.7 Device Reset

Asserting RESET low initiates the device ramp down. The output FETs go into a Hi-Z state after the ramp down is complete. Output pull downs are active both in SE mode and BTL mode with RESET low.

In BTL modes, to accommodate bootstrap charging prior to switching start, asserting the reset input low enables weak pulldown of the half-bridge outputs.

Asserting reset input low removes any fault information to be signaled on the FAULT output, that is, FAULT is forced high. A rising-edge transition on reset input allows the device to resume operation after an overload fault. To ensure thermal reliability, the rising edge of reset must occur no sooner than 4 ms after the falling edge of FAULT.



10 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

10.1 Application Information

TPA3251D2 can be configured either in stereo BTL mode, 4 channel SE mode, mono PBTL mode, or in 2.1 mixed 1x BTL + 2x SE mode depending on output power conditions and system design.

10.2 Typical Applications

10.2.1 Stereo BTL Application

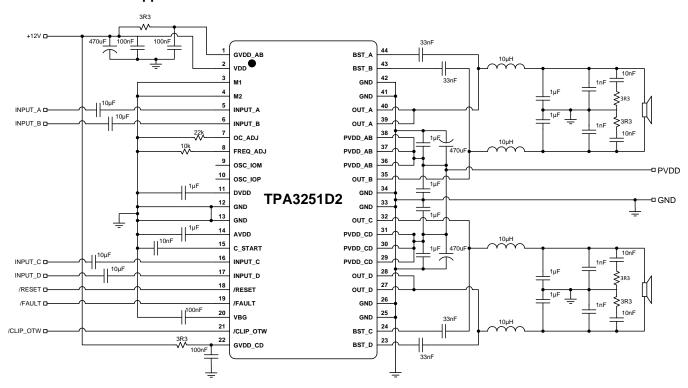


Figure 25. Typical Differential Input BTL Application



Typical Applications (continued)

10.2.1.1 Design Requirements

For this design example, use the parameters in Table 6.

Table 6. Design Requirements, BTL Application

DESIGN PARAMETER	EXAMPLE			
Low Power (Pull-up) Supply	3.3 V			
Mid Power Supply 12 V	12 V			
High Power Supply	12 - 36 V			
Mode Colection	M2 = L			
Mode Selection	M1 = L			
	INPUT_A = ±3.9 V (peak, max)			
Analog Inputo	$INPUT_B = \pm 3.9V \text{ (peak, max)}$			
Analog Inputs	INPUT_C = ±3.9 V (peak, max)			
	INPUT_D = ±3.9 V (peak, max)			
Output Filters	Inductor-Capacitor Low Pass FIlter (10 μH + 1 μF)			
Speaker Impedance	3-8 Ω			

10.2.1.2 Detailed Design Procedures

A rising-edge transition on reset input allows the device to execute the startup sequence and starts switching.

The CLIP signal is indicating that the output is approaching clipping. The signal can be used to either an audio volume decrease or intelligent power supply nominally operating at a low rail adjusting to a higher supply rail.

The device is inverting the audio signal from input to output.

The DVDD and AVDD pins are not recommended to be used as a voltage sources for external circuitry.

10.2.1.2.1 Decoupling Capacitor Recommendations

In order to design an amplifier that has robust performance, passes regulatory requirements, and exhibits good audio performance, good quality decoupling capacitors should be used. In practice, X7R should be used in this application.

The voltage of the decoupling capacitors should be selected in accordance with good design practices. Temperature, ripple current, and voltage overshoot must be considered. This fact is particularly true in the selection of the $1\mu F$ that is placed on the power supply to each full-bridge. It must withstand the voltage overshoot of the PWM switching, the heat generated by the amplifier during high power output, and the ripple current created by high power output. A minimum voltage rating of 50 V is required for use with a 36V power supply.

10.2.1.2.2 PVDD Capacitor Recommendation

The large capacitors used in conjunction with each full-bridge, are referred to as the PVDD Capacitors. These capacitors should be selected for proper voltage margin and adequate capacitance to support the power requirements. In practice, with a well designed system power supply, $1000~\mu F$, 50~V supports most applications. The PVDD capacitors should be low ESR type because they are used in a circuit associated with high-speed switching.

10.2.1.2.3 PCB Material Recommendation

FR-4 Glass Epoxy material with 2 oz. (70 μ m) copper is recommended for use with the TPA3251D2. The use of this material can provide for higher power output, improved thermal performance, and better EMI margin (due to lower PCB trace inductance.



10.2.1.2.4 Oscillator

The oscillator frequency can be trimmed by external control of the FREQ_ADJ pin.

To reduce interference problems while using radio receiver tuned within the AM band, the switching frequency can be changed from nominal to lower values. These values should be chosen such that the nominal and the lower value switching frequencies together results in the fewest cases of interference throughout the AM band. The oscillator frequency can be selected by the value of the FREQ_ADJ resistor connected to GND in master mode according to the description in the Recommended Operating Conditions table.

For slave mode operation, turn off the oscillator by pulling the FREQ_ADJ pin to DVDD. This configures the OSC_I/O pins as inputs to be slaved from an external differential clock. In a master/slave system inter channel delay is automatically setup between the switching of the audio channels, which can be illustrated by no idle channels switching at the same time. This will not influence the audio output, but only the switch timing to minimize noise coupling between audio channels through the power supply to optimize audio performance and to get better operating conditions for the power supply. The inter channel delay will be setup for a slave device depending on the polarity of the OSC_I/O connection such that a slave mode 1 is selected by connecting the master device OSC_I/O to the slave 1 device OSC_I/O with same polarity (+ to + and - to -), and slave mode 2 is selected with the inverse polarity (+ to - and - to +).

10.2.2 Application Curves

Relevant performance plots for TPA3251D2 in BTL configuration are shown in *Typical Characteristics, BTL Configuration*

Table 7. Relevant Performance Plots, BTL Configuration

PLOT TITLE	FIGURE NUMBER
Total Harmonic Distortion+Noise vs Frequency	Figure 1
Total Harmonic Distortion+Noise vs Frequency, 80kHz analyzer BW	Figure 2
Total Harmonic Distortion + Noise vs Output Power	Figure 3
Output Power vs Supply Voltage, 10% THD+N	Figure 4
Output Power vs Supply Voltage, 10% THD+N	Figure 6
System Efficiency vs Output Power	Figure 6
System Power Loss vs Output Power	Figure 7
Output Power vs Case Temperature	Figure 8
Noise Amplitude vs Frequency	Figure 9

10.2.3 Typical Application, Single Ended (1N) SE

TPA3251D2 can be configured either in stereo BTL mode, 4 channel SE mode, mono PBTL mode, or in 2.1 mixed 1x BTL + 2x SE mode depending on output power conditions and system design.

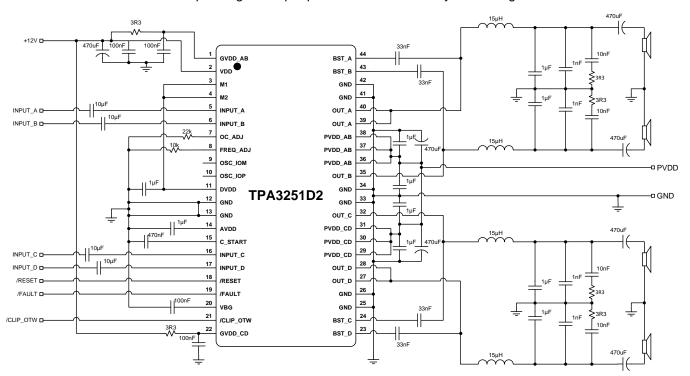


Figure 26. Typical Single Ended (1N) SE Application

10.2.3.1 Design Requirements

Refer to Stereo BTL Application for the Design Requirements.

Table 8. Design Requirements, SE Application

DESIGN PARAMETER	EXAMPLE			
Low Power (Pull-up) Supply	3.3 V			
Mid Power Supply 1 2V	12 V			
High Power Supply	12 - 36 V			
Made Calestian	M2 = H			
Mode Selection	M1 = H			
	INPUT_A = ±3.9 V (peak, max)			
Analog Inputo	INPUT_B = ±3.9 V (peak, max)			
Analog Inputs	INPUT_C = ±3.9 V (peak, max)			
	INPUT_D = ±3.9 V (peak, max)			
Output Filters	Inductor-Capacitor Low Pass Fllter (15 μH + 680 nF)			
Speaker Impedance	2 - 8 Ω			

10.2.3.2 Detailed Design Procedures

Refer to Stereo BTL Application for the Detailed Design Procedures.



10.2.3.3 Application Curves

Relevant performance plots for TPA3251D2 in PBTL configuration are shown in *Typical Characteristics*, *SE Configuration*

Table 9. Relevant Performance Plots, SE Configuration

PLOT TITLE	FIGURE NUMBER
Total Harmonic Distortion+Noise vs Output Power	Figure 10
Total Harmonic Distortion+Noise vs Frequency	Figure 11
Total Harmonic Distortion+Noise vs Frequency, 80kHz analyzer BW	Figure 12
Output Power vs Supply Voltage, 10% THD+N	Figure 13
Output Power vs Supply Voltage, 1% THD+N	Figure 14
Output Power vs Case Temperature	Figure 15

10.2.4 Typical Application, Differential (2N) PBTL

TPA3251D2 can be configured either in stereo BTL mode, 4 channel SE mode, mono PBTL mode, or in 2.1 mixed 1x BTL + 2x SE mode depending on output power conditions and system design.

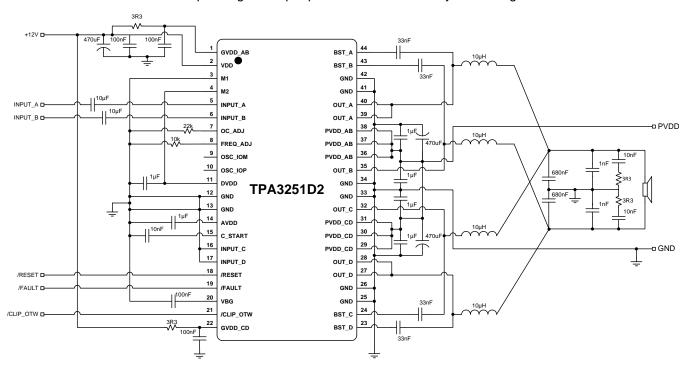


Figure 27. Typical Differential (2N) PBTL Application

10.2.4.1 Design Requirements

Refer to Stereo BTL Application for the Design Requirements.

Table 10. Design Requirements, PBTL Application

DESIGN PARAMETER	EXAMPLE			
Low Power (Pull-up) Supply	3.3 V			
Mid Power Supply 12 V	12 V			
High Power Supply	12 - 36 V			
Made Colorian	M2 = H			
Mode Selection	M1 = L			
	INPUT_A = ±3.9V (peak, max)			
Analog Inputs	INPUT_B = ±3.9V (peak, max)			
Analog Inputs	INPUT_C = Grounded			
	INPUT_D = Grounded			
Output Filters	Inductor-Capacitor Low Pass FIlter (10 μH + 1 μF)			
Speaker Impedance	2 - 4 Ω			

10.2.4.2 Detailed Design Procedures

Refer to Stereo BTL Application for the Detailed Design Procedures.



10.2.4.3 Application Curves

Relevant performance plots for TPA3251D2 in PBTL configuration are shown in *Typical Characteristics, PBTL Configuration*

Table 11. Relevant Performance Plots, PBTL Configuration

PLOT TITLE	FIGURE NUMBER
Total Harmonic Distortion+Noise vs Output Power	Figure 16
Total Harmonic Distortion+Noise vs Frequency	Figure 17
Total Harmonic Distortion+Noise vs Frequency, 80kHz analyzer BW	Figure 18
Output Power vs Supply Voltage, 10% THD+N	Figure 19
Output Power vs Supply Voltage, 1% THD+N	Figure 20
Output Power vs Case Temperature	Figure 21

11 Power Supply Recommendations

11.1 Power Supplies

The TPA3251D2 device requires two external power supplies for proper operation. A high-voltage supply called PVDD is required to power the output stage of the speaker amplifier and its associated circuitry. Additionally, one mid-voltage power supply for GVDD_X and VDD is required to power the gate-drive and other internal digital and analog portions of the device. The allowable voltage range for both the PVDD and the GVDD_X/VDD supplies are listed in the *Recommended Operating Conditions* table. Ensure both the PVDD and the GVDD_X/VDD supplies can deliver more current than listed in the *Electrical Characteristics* table.

11.1.1 VDD Supply

The VDD supply required from the system is used to power several portions of the device. It provides power to internal regulators DVDD and AVDD that are used to power digital and analog sections of the device, respectively. Proper connection, routing, and decoupling techniques are highlighted in the TPA3251D2 device EVM User's Guide SLVUAG8 (as well as the *Application Information* section and *Layout Examples* section) and must be followed as closely as possible for proper operation and performance. Deviation from the guidance offered in the TPA3251D2 device EVM User's Guide, which followed the same techniques as those shown in the *Application Information* section, may result in reduced performance, errant functionality, or even damage to the TPA3251D2 device. Some portions of the device also require a separate power supply which is a lower voltage than the VDD supply. To simplify the power supply requirements for the system, the TPA3251D2 device includes integrated low-dropout (LDO) linear regulators to create these supplies. These linear regulators are internally connected to the VDD supply and their outputs are presented on AVDD and DVDD pins, providing a connection point for an external bypass capacitors. It is important to note that the linear regulators integrated in the device have only been designed to support the current requirements of the internal circuitry, and should not be used to power any additional external circuitry. Additional loading on these pins could cause the voltage to sag and increase noise injection, which negatively affects the performance and operation of the device.

11.1.2 GVDD X Supply

The GVDD_X supply required from the system is used to power the gate-drives for the output H-bridges. Proper connection, routing, and decoupling techniques are highlighted in the TPA3251D2 device EVM User's Guide SLVUAG8 (as well as the *Application Information* section and *Layout Examples* section) and must be followed as closely as possible for proper operation and performance. Deviation from the guidance offered in the TPA3251D2 device EVM User's Guide, which followed the same techniques as those shown in the *Application Information* section, may result in reduced performance, errant functionality, or even damage to the TPA3251D2 device.



Power Supplies (continued)

11.1.3 PVDD Supply

The output stage of the speaker amplifier drives the load using the PVDD supply. This is the power supply which provides the drive current to the load during playback. Proper connection, routing, and decoupling techniques are highlighted in the TPA3251D2 device EVM User's Guide SLVUAG8 (as well as the *Application Information* section and *Layout Examples* section) and must be followed as closely as possible for proper operation and performance. Due the high-voltage switching of the output stage, it is particularly important to properly decouple the output power stages in the manner described in the TPA3251D2 device EVM User's Guide SLVUAG8. The lack of proper decoupling, like that shown in the EVM User's Guide, can results in voltage spikes which can damage the device, or cause poor audio performance and device shutdown faults.

11.2 Powering Up

The TPA3251D2 does not require a power-up sequence, but it is recommended to hold RESET low minimum 400ms after PVDD supply voltage is turned ON. The outputs of the H-bridges remain in a high-impedance state until the gate-drive supply voltage (GVDD_X) and VDD voltage are above the undervoltage protection (UVP) voltage threshold (see the *Electrical Characteristics* table of this data sheet). This allows an internal circuit to charge the external bootstrap capacitors by enabling a weak pulldown of the half-bridge output as well as initiating a controlled ramp up sequence of the output voltage.

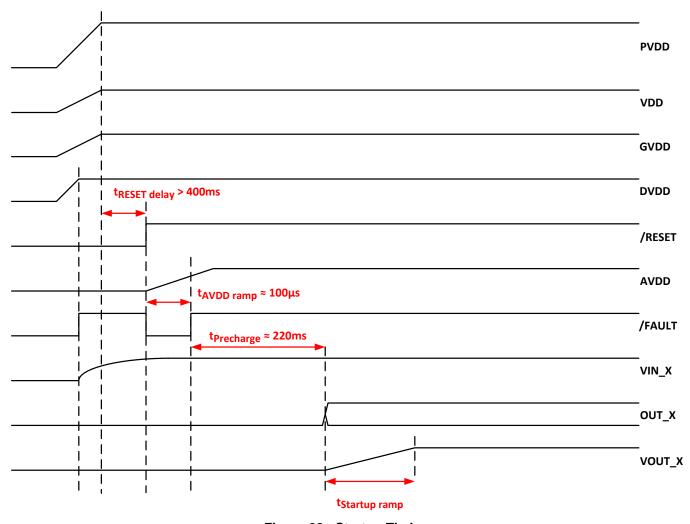


Figure 28. Startup Timing



Powering Up (continued)

When RESET is released to turn on TPA3251D2, FAULT signal will turn low and AVDD voltage regulator will be enabled. FAULT will stay low until AVDD reaches the undervoltage protection (UVP) voltage threshold (see the Electrical Characteristics table of this data sheet). After a precharge time to stabilize the DC voltage across the input AC coupling capacitors, before the ramp up sequence starts.

11.3 Powering Down

The TPA3251D2 does not require a power-down sequence. The device remains fully operational as long as the gate-drive supply (GVDD_X) voltage and VDD voltage are above the undervoltage protection (UVP) voltage threshold (see the *Electrical Characteristics* table of this data sheet). Although not specifically required, it is a good practice to hold RESET low during power down, thus preventing audible artifacts including pops or clicks by initiating a controlled ramp down sequence of the output voltage.

12 Layout

12.1 Layout Guidelines

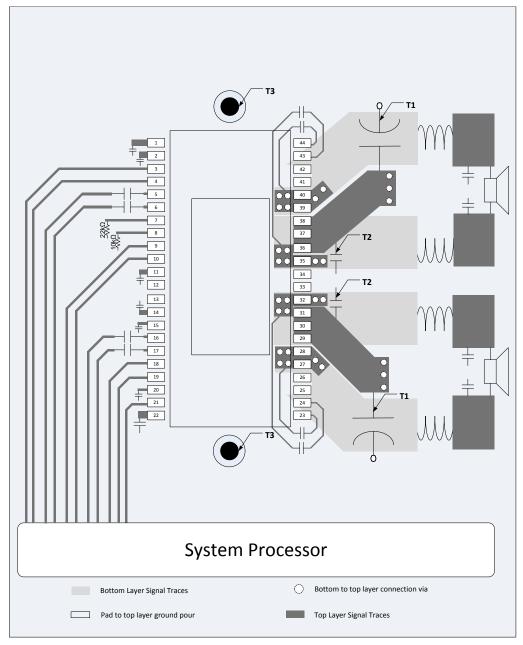
- Use an unbroken ground plane to have good low impedance and inductance return path to the power supply for power and audio signals.
- Maintain a contiguous ground plane from the ground pins to the PCB area surrounding the device for as many of the ground pins as possible, since the ground pins are the best conductors of heat in the package.
- PCB layout, audio performance and EMI are linked closely together.
- · Routing the audio input should be kept short and together with the accompanied audio source ground.
- The small bypass capacitors on the PVDD lines of the DUT be placed as close the PVDD pins as possible.
- A local ground area underneath the device is important to keep solid to minimize ground bounce.
- Orient the passive component so that the narrow end of the passive component is facing the TPA3251D2 device, unless the area between two pads of a passive component is large enough to allow copper to flow in between the two pads.
- Avoid placing other heat producing components or structures near the TPA3251D2 device.
- Avoid cutting off the flow of heat from the TPA3251D2 device to the surrounding ground areas with traces or via strings, especially on output side of device.

Netlist for this printed circuit board is generated from the schematic in Figure 29.



12.2 Layout Examples

12.2.1 BTL Application Printed Circuit Board Layout Example



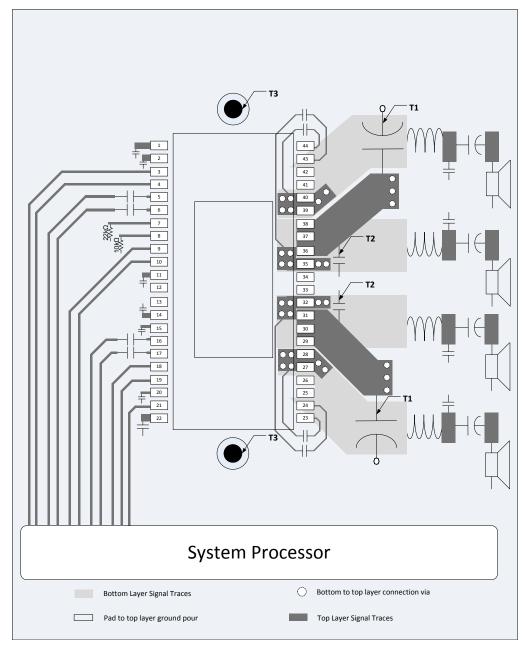
- A. Note: PCB layout example shows composite layout. Dark grey: Top layer copper traces, light gray: Bottom layer copper traces. All PCB area not used for traces should be GND copper pour (transparent on example image)
- B. **Note T1**: PVDD decoupling bulk capacitors should be as close as possible to the PVDD and GND_X pins, the heat sink sets the distance. Wide traces should be routed on the top layer with direct connection to the pins and without going through vias. No vias or traces should be blocking the current path.
- C. **Note T2**: Close decoupling of PVDD with low impedance X7R ceramic capacitors is placed under the heat sink and close to the pins.
- Note T3: Heat sink needs to have a good connection to PCB ground.

Figure 29. BTL Application Printed Circuit Board - Composite



Layout Examples (continued)

12.2.2 SE Application Printed Circuit Board Layout Example



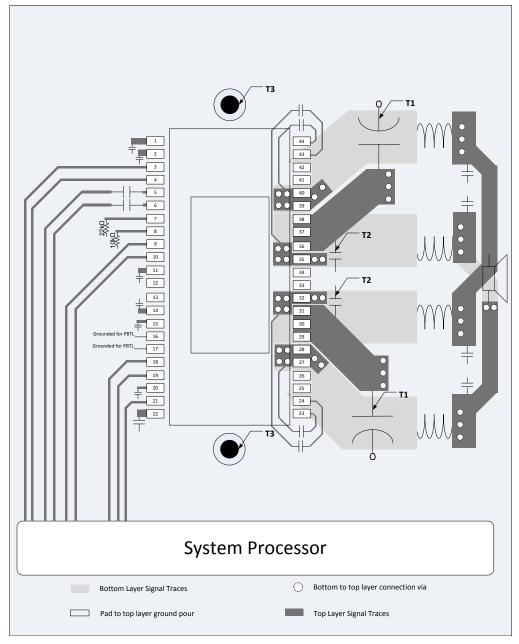
- A. Note: PCB layout example shows composite layout. Dark grey: Top layer copper traces, light gray: Bottom layer copper traces. All PCB area not used for traces should be GND copper pour (transparent on example image)
- B. **Note T1**: PVDD decoupling bulk capacitors should be as close as possible to the PVDD and GND_X pins, the heat sink sets the distance. Wide traces should be routed on the top layer with direct connection to the pins and without going through vias. No vias or traces should be blocking the current path.
- C. **Note T2**: Close decoupling of PVDD with low impedance X7R ceramic capacitors is placed under the heat sink and close to the pins.
- D. Note T3: Heat sink needs to have a good connection to PCB ground.

Figure 30. SE Application Printed Circuit Board - Composite



Layout Examples (continued)

12.2.3 PBTL Application Printed Circuit Board Layout Example



- A. Note: PCB layout example shows composite layout. Dark grey: Top layer copper traces, light gray: Bottom layer copper traces. All PCB area not used for traces should be GND copper pour (transparent on example image)
- B. **Note T1**: PVDD decoupling bulk capacitors should be as close as possible to the PVDD and GND_X pins, the heat sink sets the distance. Wide traces should be routed on the top layer with direct connection to the pins and without going through vias. No vias or traces should be blocking the current path.
- C. **Note T2**: Close decoupling of PVDD with low impedance X7R ceramic capacitors is placed under the heat sink and close to the pins.
- D. ote T3: Heat sink needs to have a good connection to PCB ground.

Figure 31. PBTL Application Printed Circuit Board - Composite



13 器件和文档支持

13.1 文档支持

《TPA3251D2EVM 用户指南》, SLVUAG8

13.2 社区资源

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

13.3 商标

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13.4 静电放电警告



这些装置包含有限的内置 ESD 保护。 存储或装卸时,应将导线一起截短或将装置放置于导电泡棉中,以防止 MOS 门极遭受静电损伤。

13.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

14 机械、封装和可订购信息

以下页中包括机械、封装和可订购信息。 这些信息是针对指定器件可提供的最新数据。 这些数据会在无通知且不对本文档进行修订的情况下发生改变。 欲获得该数据表的浏览器版本,请查阅左侧的导航栏。

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TPA3251D2DDV	ACTIVE	HTSSOP	DDV	44	35	RoHS & Green	NIPDAU	Level-3-260C-168 HR	0 to 70	3251	Samples
TPA3251D2DDVR	ACTIVE	HTSSOP	DDV	44	2000	RoHS & Green	NIPDAU	Level-3-260C-168 HR	0 to 70	3251	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE OPTION ADDENDUM

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TPA3251D2DDVR	HTSSOP	DDV	44	2000	330.0	24.4	8.6	15.6	1.8	12.0	24.0	Q1

PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

	Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
I	TPA3251D2DDVR	HTSSOP	DDV	44	2000	350.0	350.0	43.0

PACKAGE MATERIALS INFORMATION

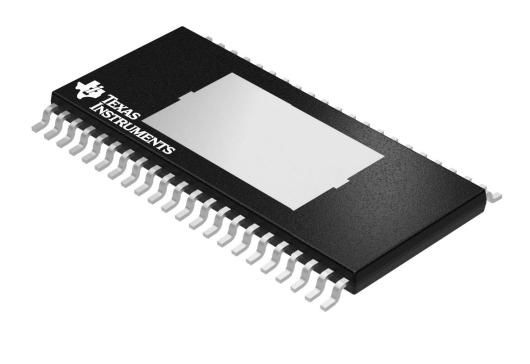
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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TPA3251D2DDV	DDV	HTSSOP	44	35	530	11.89	3600	4.9

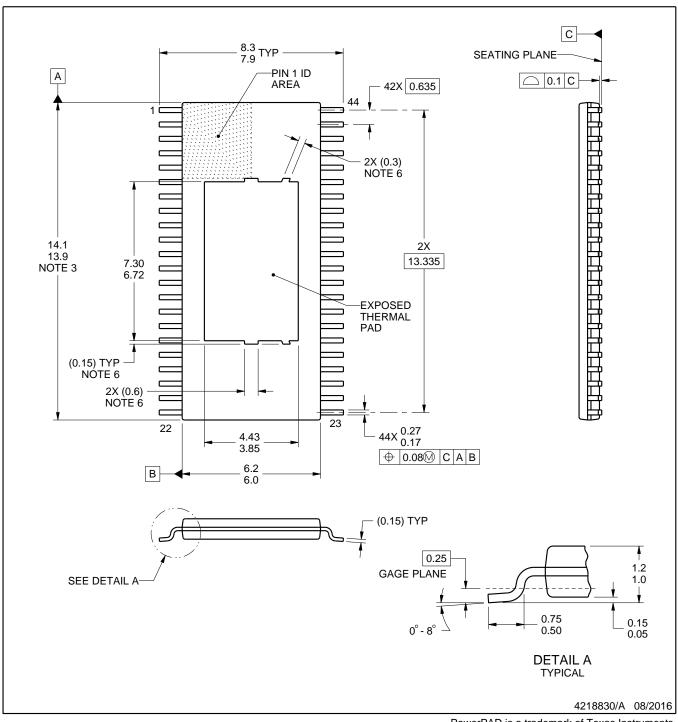


Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.

4206011/H







NOTES:

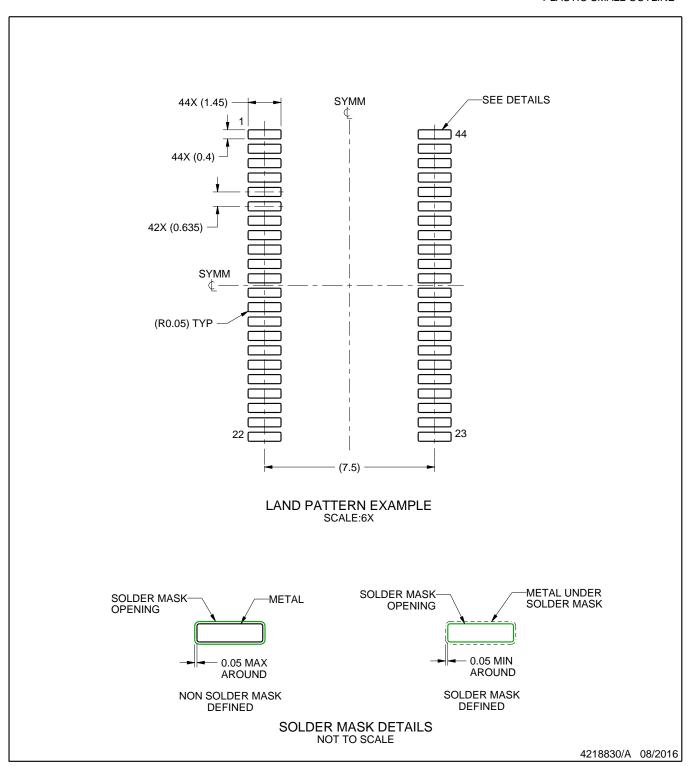
PowerPAD is a trademark of Texas Instruments.

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
 4. Reference JEDEC registration MO-153.
- 5. The exposed thermal pad is designed to be attached to an external heatsink.
- 6. Features may differ or may not be present.

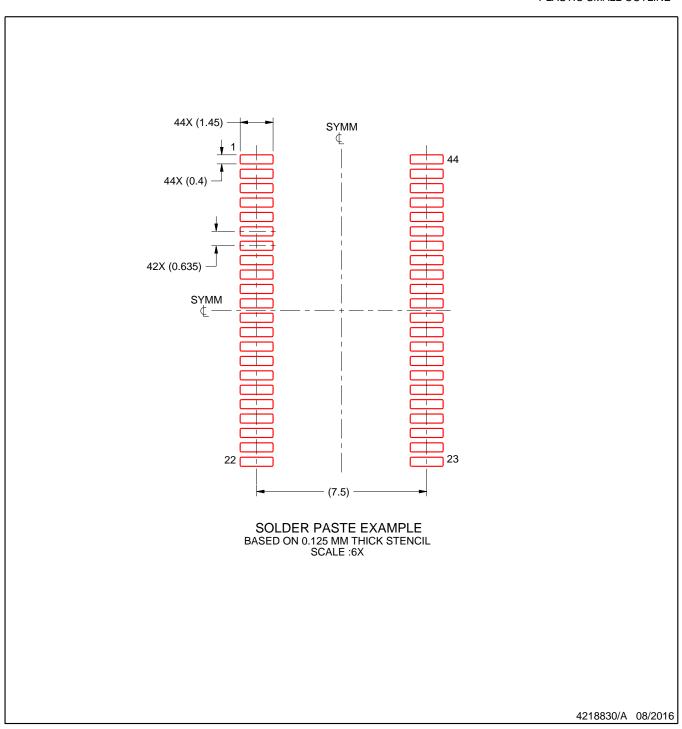




NOTES: (continued)

- 7. Publication IPC-7351 may have alternate designs.
- 8. Solder mask tolerances between and around signal pads can vary based on board fabrication site.





NOTES: (continued)

- 9. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 10. Board assembly site may have different recommendations for stencil design.



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